DISCRETE SEMICONDUCTORS

DATA SHEET



BF1211; BF1211R; BF1211WR N-channel dual-gate MOS-FETs

Product specification

2003 Dec 16





N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

FEATURES

- Short channel transistor with high forward transfer admittance to input capacitance ratio
- · Low noise gain controlled amplifier
- · Excellent low frequency noise performance
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

APPLICATIONS

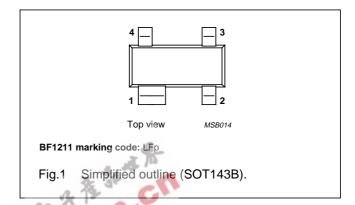
 Gain controlled low noise VHF and UHF amplifiers for 5 V digital and analog television tuner applications.

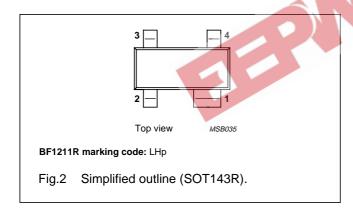
DESCRIPTION

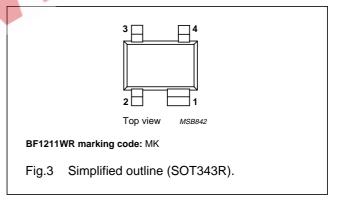
Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1211, BF1211R and BF1211WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.

PINNING

PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1







QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{DS}	drain-source voltage		_	_	6	V
I _D	drain current		_	_	30	mA
P _{tot}	total power dissipation		_	_	180	mW
y _{fs}	forward transfer admittance		25	30	40	mS
C _{ig1-ss}	input capacitance at gate 1		_	2.1	2.6	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	f = 400 MHz	_	0.9	1.6	dB
X _{mod}	cross-modulation	input level for k = 1% at 40 dB AGC	100	105	_	dBμV
T _j	junction temperature		_	_	150	°C

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

CAUTION

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling. For further information, refer to Philips specs.: SNW-EQ-608, SNW-FQ-302A and SNW-FQ-302B.

ORDERING INFORMATION

TYPE NUMBER		PACKAGE				
I TPE NUMBER	NAME	DESCRIPTION	VERSION			
BF1211	 plastic surface mounted package; 4 leads 		SOT143B			
BF1211R	_	plastic surface mounted package; reverse pinning; 4 leads				
BF1211WR	 plastic surface mounted package; reverse pinning; 4 leads 		SOT343R			

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	drain-source voltage	3c 3t	40	6	V
I_D	drain current (DC)	237	1	30	mA
I _{G1}	gate 1 current	132	_	±10	mA
I_{G2}	gate 2 current	A C	_	±10	mA
P _{tot}	total power dissipation				
	BF1211; BF1211R	T _s ≤ 116 °C; note 1	_	180	mW
	BF1211WR	T _s ≤ 122 °C; note 1	_	180	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		_	150	°C

Note

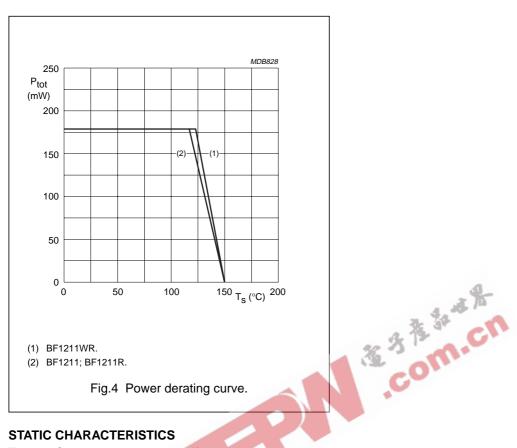
THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R _{th(j-s)}	thermal resistance from junction to soldering point		
	BF1211; BF1211R	185	K/W
	BF1211WR	155	K/W

^{1.} T_s is the temperature of the soldering point of the source lead.

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



STATIC CHARACTERISTICS

T_i = 25 °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{(BR)DSS}	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0 \text{ V}; I_D = 10 \mu\text{A}$	6	_	٧
V _{(BR)G1-SS}	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{G1-S} = 10 \text{ mA}$	6	10	٧
V _{(BR)G2-SS}	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{G2-S} = 10 \text{ mA}$	6	10	V
V _{(F)S-G1}	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{S-G1} = 10 \text{ mA}$	0.5	1.5	V
V _{(F)S-G2}	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{S-G2} = 10 \text{ mA}$	0.5	1.5	V
V _{G1-S(th)}	gate 1-source threshold voltage	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1	V
V _{G2-S(th)}	gate 2-source threshold voltage	threshold voltage $V_{G1-S} = 5 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$		1	٧
I _{DSX}	drain-source current	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; R_{G1} = 75 \text{ k}\Omega;$ note 1	11	19	mA
I _{G1-S}	gate 1 cut-off current	V _{G2-S} = V _{DS} = 0 V; V _{G1-S} = 5 V	_	50	nA
I _{G2-S}	gate 2 cut-off current	$V_{G1-S} = V_{DS} = 0 \text{ V}; V_{G2-S} = 4 \text{ V}$	_	20	nA

Note

1. R_{G1} connects G_1 to $V_{GG} = 5$ V.

2003 Dec 16 4

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

DYNAMIC CHARACTERISTICS

Common source; T_{amb} = 25 °C; V_{G2-S} = 4 V; V_{DS} = 5 V; I_D = 15 mA; unless otherwise specified.

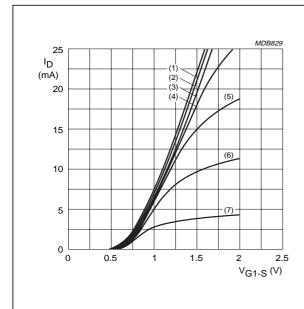
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
y _{fs}	forward transfer admittance	pulsed; T _j = 25 °C	25	30	40	mS
C _{ig1-ss}	input capacitance at gate 1	f = 1 MHz	_	2.1	2.6	pF
C _{ig2-ss}	input capacitance at gate 2	f = 1 MHz	_	1.1	_	pF
Coss	output capacitance	f = 1 MHz	_	0.9	_	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	$f = 11 \text{ MHz}; G_S = 20 \text{ mS}; B_S = 0$	_	3.5	_	dB
		f = 400 MHz; Y _S = Y _{S (opt)}	_	0.9	1.6	dB
		$f = 800 \text{ MHz}; Y_S = Y_{S \text{ (opt)}}$	_	1.3	2	dB
G _{tr}	power gain	$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	34	_	dB
		$G_L = 0.5 \text{ mS}$; $B_L = B_{L \text{ (opt)}}$				
		$f = 400 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	29	_	dB
		$G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$	5			
		$f = 800 \text{ MHz}; G_S = 3.3 \text{ mS}; B_S = B_{S \text{ (opt)}};$	-	24	_	dB
		$G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
X_{mod}	cross-modulation	input level for k = 1%; f _w = 50 MHz;				
		f _{unw} = 60 MHz; note 1				
		at 0 dB AGC	90	-	_	dΒμV
		at 10 dB AGC	_	92	_	dΒμV
		at 40 dB AGC	100	105	_	dΒμV

Note

1. Measured in test circuit Fig.21.

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



 $V_{DS} = 5 \text{ V}; T_j = 25 ^{\circ}\text{C}.$

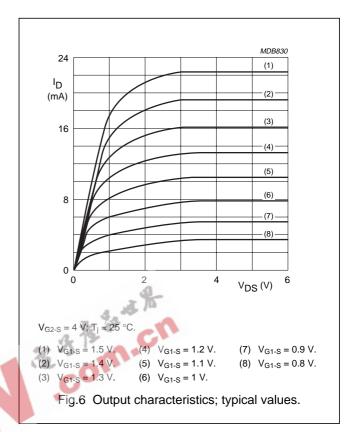
- (1) $V_{G2-S} = 4 V$.
- (4) $V_{G2-S} = 2.5 \text{ V}.$
- (7) $V_{G2-S} = 1 V$.
- (2) $V_{G2-S} = 3.5 \text{ V}.$ (3) $V_{G2-S} = 3 \text{ V}.$

(2) $V_{G2-S} = 3.5 \text{ V}.$

(3) $V_{G2-S} = 3 V$.

(5) $V_{G2-S} = 2 \text{ V}$. (6) $V_{G2-S} = 1.5 \text{ V}$.

Fig.5 Transfer characteristics; typical values.



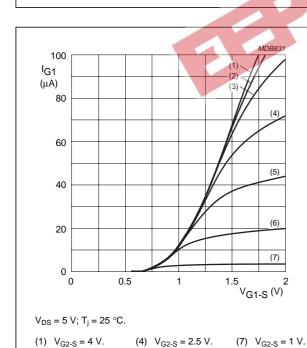
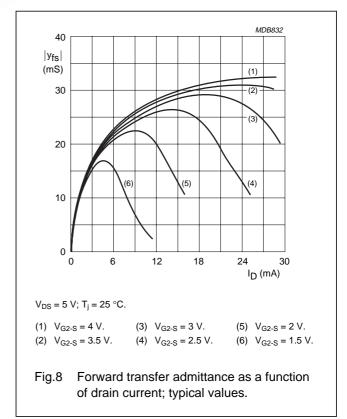


Fig.7 Gate 1 current as a function of gate 1 voltage; typical values.

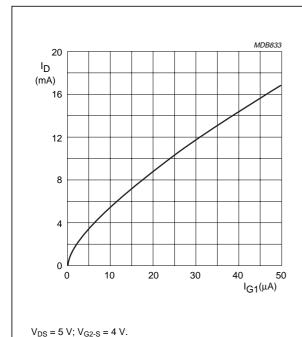
(5) $V_{G2-S} = 2 V$.

(6) $V_{G2-S} = 1.5 \text{ V}.$



N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



 $T_j = 25 \, ^{\circ}\text{C}.$

Fig.9 Drain current as a function of gate 1 current; typical values.

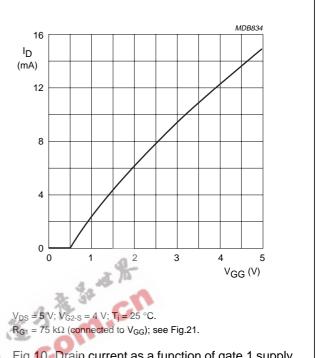
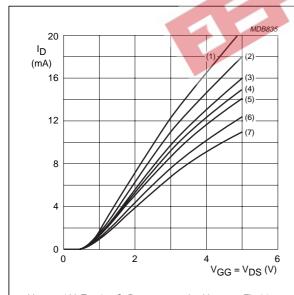


Fig. 10 Drain current as a function of gate 1 supply voltage (V_{GG}); typical values.

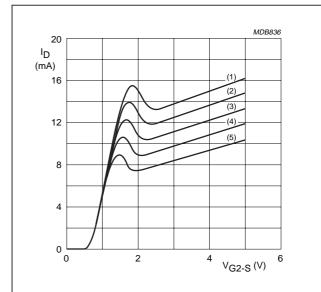


 $V_{G2\text{-S}}$ = 4 V; T_{j} = 25 °C; R_{G1} connected to V_{GG} ; see Fig.21.

- (1) $R_{G1} = 47 \text{ k}\Omega$.
- (4) $R_{G1} = 75 \text{ k}\Omega$.
- (7) $R_{G1} = 120 \text{ k}\Omega$.

- (2) $R_{G1} = 56 \text{ k}\Omega$. (3) $R_{G1} = 68 \text{ k}\Omega$.
- (5) $R_{G1} = 82 \text{ k}\Omega$.
- 3) $R_{G1} = 68 \text{ k}\Omega$. (6) $R_{G1} = 100 \text{ k}\Omega$.

Fig.11 Drain current as a function of gate 1 (V_{GG}) and drain supply voltage; typical values.



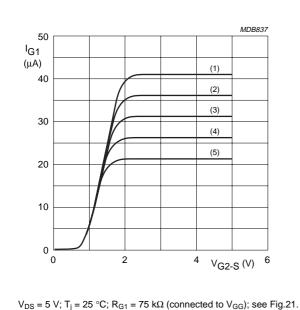
 V_{DS} = 5 V; T_{j} = 25 °C; R_{G1} = 75 $k\Omega$ (connected to V_{GG}); see Fig.21.

- (1) $V_{GG} = 5 \text{ V}.$
- (4) $V_{GG} = 3.5 \text{ V}.$
- (2) $V_{GG} = 4.5 \text{ V}.$
- (5) $V_{GG} = 3 \text{ V}.$
- (3) $V_{GG} = 4 V$.

Fig.12 Drain current as a function of gate 2 voltage; typical values.

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



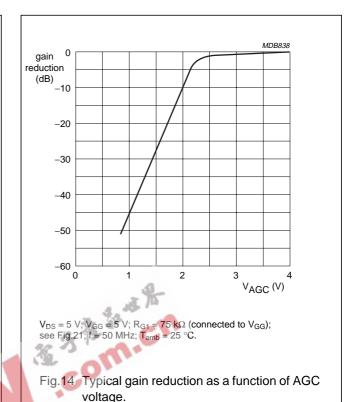
(1) $V_{GG} = 5 \text{ V}.$

2003 Dec 16

- (3) $V_{GG} = 4 V$.
- (5) $V_{GG} = 3 V$.

- (2) $V_{GG} = 4.5 \text{ V}.$
- (4) $V_{GG} = 3.5 \text{ V}.$

Fig.13 Gate 1 current as a function of gate 2 voltage; typical values.



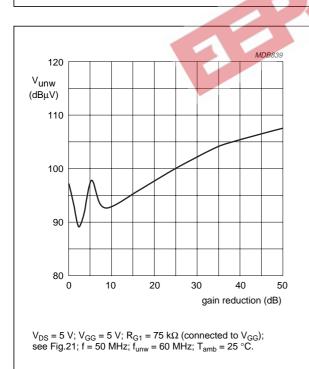
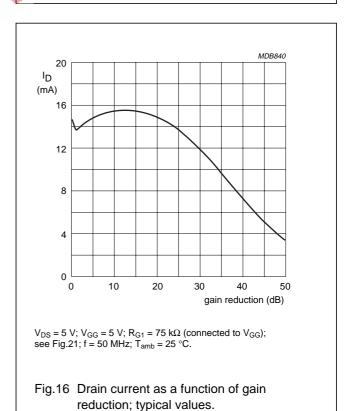


Fig.15 Unwanted voltage for 1% cross-modulation as a function of gain reduction; typical values.



8

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

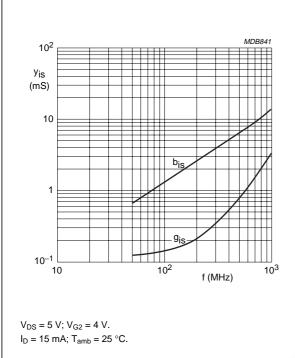
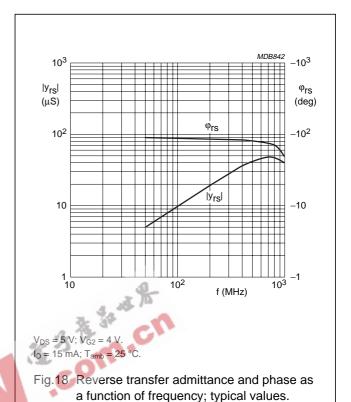
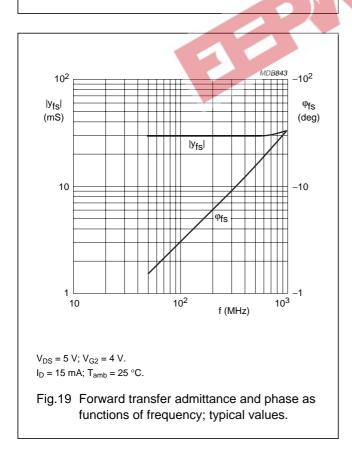
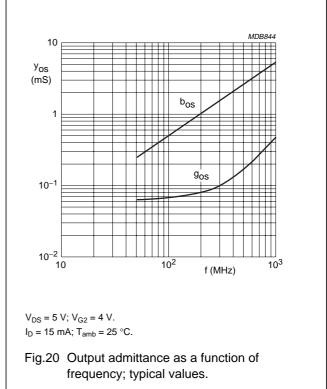


Fig.17 Input admittance as a function of frequency; typical values.







N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

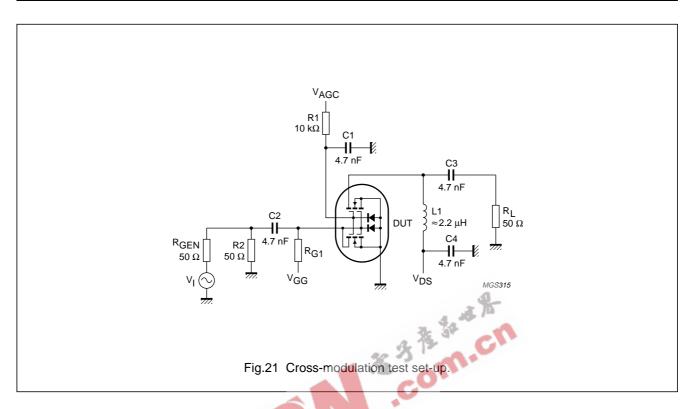


Table 1 Scattering parameters: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 15 \text{ mA}$; $T_{amb} = 25 \text{ °C}$

	S ₁₁		\$ ₂₁		S ₁₂		S ₂₂	
(MHz)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.987	-3.86	2.928	175.8	0.0005	89.3	0.993	-1.58
100	0.985	-7.73	2.921	171.6	0.0010	86.9	0.993	-3.14
200	0.979	-15.25	2.807	163.2	0.0015	91.1	0.993	-6.31
300	0.965	-22.84	2.846	155.0	0.0028	77.4	0.988	-9.41
400	0.949	-30.15	2.784	146.7	0.0034	74.0	0.985	-12.48
500	0.929	-30.25	2.704	138.9	0.0037	71.4	0.981	-15.54
600	0.904	-44.24	2.639	130.9	0.0040	69.6	0.976	-18.59
700	0.876	-51.16	2.558	123.0	0.0039	69.0	0.971	-21.65
800	0.846	-58.16	2.486	115.1	0.0037	70.0	0.965	-24.27
900	0.816	-65.15	2.402	107.2	0.0032	74.5	0.960	-27.79
1000	0.791	-72.22	2.315	99.9	0.0028	87.1	0.956	-30.94

Table 2 Noise data: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 15 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

f	F _{min}	Γ	opt	R _n
(MHz)	(dB)	(ratio)	(deg)	(Ω)
400	0.9	0.693	16.75	29.85
800	1.3	0.707	37.33	29.90

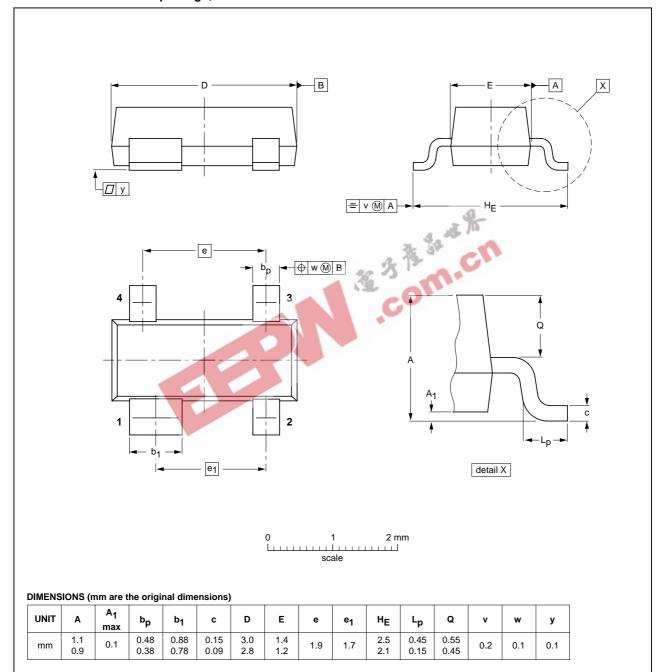
N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

PACKAGE OUTLINES

Plastic surface mounted package; 4 leads

SOT143B



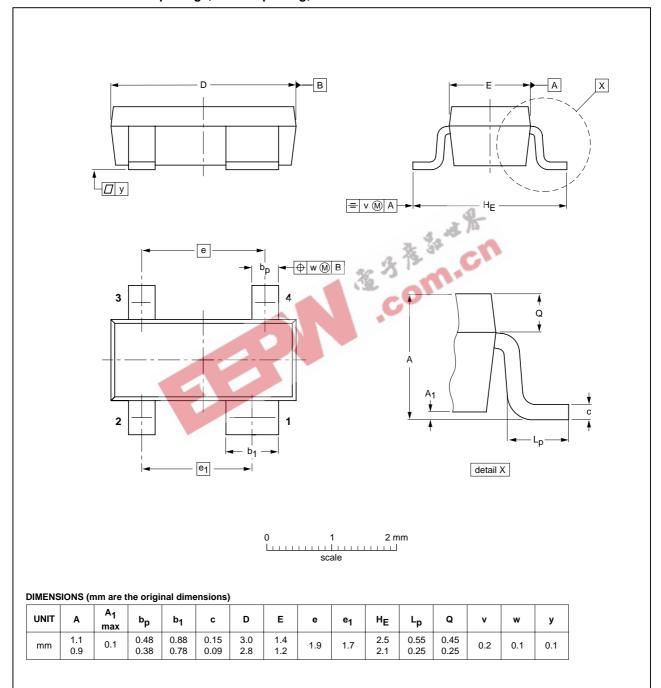
OUTLINE	REFERENCES				EUROPEAN ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT143B						97-02-28	

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT143R



OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT143R			SC-61B			97-03-10 99-09-13

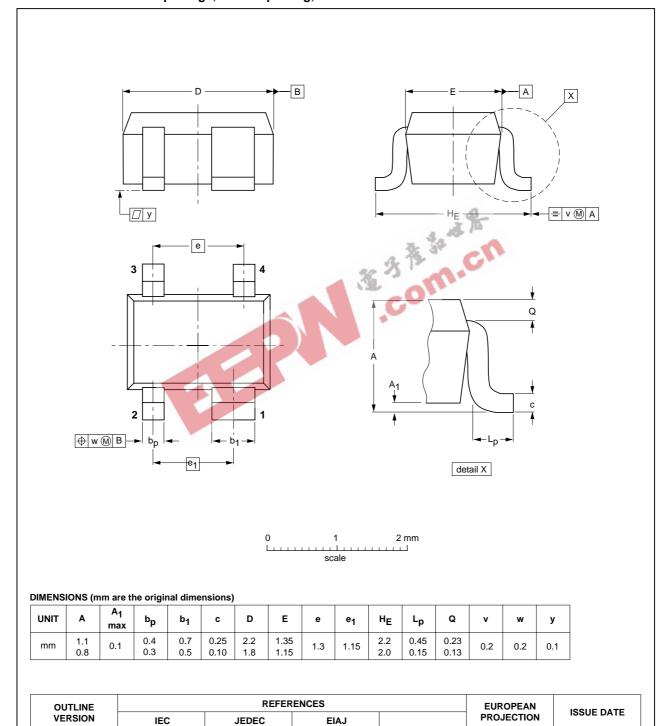
N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

97-05-21

Plastic surface mounted package; reverse pinning; 4 leads

SOT343R



2003 Dec 16 13

SOT343R

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

DATA SHEET STATUS

LEVEL	DATA SHEET STATUS ⁽¹⁾	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

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- 2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
- 3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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